		1	JC17 Rec'd PCT/PTO 1.8 MAY 2001				
Prepared from FORM PTO-1390		Transmittal Letter to the United St Designated/Electod Office (DO/EO	tates Page 1				
Customer No.		026418					
Attorney's Docket No.:		GK-ZEI-3126 / 500343.20127					
U.S. Application No.:		09/856222					
International Application No.:		PCT/EP00/09199					
International Filing Date:		SEPTEMBER 20, 2000	20 SEPTEMBER 2000				
Priority Date Claimed:		SEPTEMBER 29, 1999	29 SEPTEMBER 1999				
Title of Invention:		MICROSCOPE, ESPECIALLY MICROSCOPE USED FOR INSPECTION IN SEMICONDUCTOR MANUFACTURE					
Applicant(s) for (DO/EO/US):		Thomas ENGEL, Wolfgang HARNISCH and Roland SCHELER					
Applica	nt herewith submits to t	he United States Designated/Elected Office (DO/E	O/US) the following items and other information:				
[X] 1. [] 2. [] 3. [] 4. [X] 5. [X] 5. [A] 5. [B] 9. [B] 10.	This is a SECOND or This express request to examination until the examination of the International and is translation of the International and and the examination of the International and the examination of the International and International and International Atranslation of the International Atranslation of the International Atranslation of the International Int	conal Application as filed [35 U.S.C. 371(c)(2)] mitted herewith (required only if not transmitted by an transmitted by the international Bureau equired, as the application was filed in the United Scernational Application into English [35 U.S.C. 371(aims of the International Application under PCT Arasmitted herewith (required only if not transmitted been transmitted by the International Bureau to been made; however, the time limit for making such been made and will not be made nendments to the claims under PCT Article 19 [35 In of the inventor(s) [35 U.S.C. 371(c)(4)] Executed nexes to the International Preliminary Examination	filing under 35 U.S.C. 371. C. 371 (f)] at any time rather than delay U.S.C. 371(b) and PCT Articles 22 and by the 19th month from the the International Bureau) tates Receiving Office (RO/US) (c)(2)] TO FOLLOW ticle 19 [35 U.S.C. 371(c)(3)] by the International Bureau) uch amendments has NOT expired. U.S.C. 371(c)(3)] Deci/POA TO FOLLOW				
Items 1	•	rn other document(s) or information included:					
	An Information Disclosure Statement under 37 C.F.R. 1.97 and 1.98 An Assignment document for recording. A separate cover sheet (PTO-1619A) in compliance with 37 CFR 3.28 and 3.31 is included. _ A FIRST preliminary amendment _ A SECOND or SUBSEQUENT preliminary amendment						
[] * 14.	A substitute specifica	ation					
[] 15.		attorney and/or address letter	NO 04/00040 F4 DD04				
[X] 16.		ation) PCT/RO/101 and Publication No. WO 01/23940 5APR01 and					
	Search Report (PCT/ISA/210 dated 6MAR01					

THIS APPLICATION IS FILED IN THE GERMAN LANGUAGE

EXPRESS MAIL No		Deposited:	May 18, 2001	₹,
I hereby ceptify that	this correspondence is being depos	sited with the United Sta	ates Postal Service Exp	ress mail under 37 CFR 1.10
on the date indicate	d above and is addressed to: BOX	PCT, Commissioner for	r Patents, Washington,	DC 20231.
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(Ruth Montalvo Date: May 18, 2001

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U.S. Application No. (if known, see 37 C.S. R. 1.50 International Application No.: PCT/EF)): سند ,	. 3	Attorney's	s Do	ck	GK-ZE	El-3126 / 5003	・ノし 43.20) <u> </u>	9
indinatorial/Application (16.17 CT/21)					Citt		ALCULATIONS		USE ON	LY
[X] 17. The following fees are submitted: BASIC NATIONAL FEE [37 CF	R 1.492(a)(1	1)-(5)]			J	C18 Rec'd	I PCT/PTO	1 8	MAY	20
[X] Search Report has been prepared by the	EPO or JPC	D		. \$		860.00				
[] International preliminary examination fee paid to USPTO [37 CFR 1.482] \$ 690.00						690.00				
[] No International preliminary examination fee paid to USPTO [37 CFR 1.482] but International search fee paid to USPTO [37 CFR 1.445(a)(2) \$ 710.00						710.00				
[] Neither International preliminary examinternational search fee [37 CFR 1.445(a)(3)		-	-	\$		1,000.00				
[] International preliminary examination and all claims satisfied provisions of PCT						100.00				
ENTER APPROPRIATE BASIC FEE AMOUNT:							\$860.00			
Claims	Number Filed		Number Extra	Ra	ate					
Total Claims Indep. Claims	5	-20 -03	LAUG	×	\$	18. = 80. =				
[] Multiple Dependent Claim(s) (if applicable)	<u> </u>	-03	<u></u>			270. =		-		
	TO	OTAL	OF ABOVE (\$860.00	+-		
Surcharge of \$130.00 for furnishing the oath or de earliest claimed priority date [37 CFR 1.492(e)]										
	T	OTAL (OF ABOVE (CAL	CUI	_ATIONS:	\$860.00	+	<u> </u>	
Applicant claims Small Entity Status [See 37 CFR	1.27] Reduc	tion by	½ for filing b	y sı	mall	entity				
2.3 3 par :					SU	BTOTAL:	\$860.00	1		
Processing fee of \$130.00 for furnishing the English the earliest claimed priority date [37 CFR 1.492(f)]		n later	than [] 20 [] 30	mo	nths from				
						NAL FEE:	\$860.00			
Fee for recording the enclosed assignment [37 CFF by an appropriate cover sheet (PTO-1595) [37 CFR 3	R 1.21(h)] The 3.28, 3.31].\$ 4	e assig 0.00 pe	nment must r property	be a	acco	mpanied +				
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			AMOUNT REFUNDE				REFUNDED CHARGED	\$		
[X] Check in the amount of \$860.00 to cover any additional fees required with this su NOTE: Where an appropriate time limit under 36	bmission or CFR 1.494	or 1.49	lit any overpa 95 has not be	en r	ent	to Deposit A	Account No: 5	0-152	9.)	ge
or (b)] must be filed and granted to restore	the applicati	ion to j	pending statu	ıs.						
SEND ALL CORRESPONDENCE TO: Gerald h. Kiel, Esq. (Customer No. Reed Smith LLP 375 Park Avenue New York, NY 10152	5. 026418) H.Li									
Gerald H. Kiel Name (Tel. (212) 521-5400) Signature	J - 50	•		25,1 Reg.		<u>Ma</u> Da	te			



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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SUBSTITUTE SPECIFICATION And ABSTRACT